Sear	rch N	otes	(contii	nued)

)	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/941,592	TAJIMA, HISAO
	Examiner	Art Unit
	M. Lee	2614

SEARCHED			
Class	Subclass	Date	Examiner
348	836	1/23/2006	ML
	838		
	839		
361	683		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	,		_

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE EXMR		
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Application No.	Applicant(s)	
09/941,592	TAJIMA, HISAO	
Examiner	Art Unit	
M. Lee	2614	

SEARCHED			
Class	Subclass	Date	Examiner
348	552	11/11/2004	ML
348	14.04	8/23/2005	ML
348	14.01	1/23/2006	ML
348	373		
348	375		
361	686		
361	681	_	
361	687		
248	231.31		
248	187.1		
248	229.11		
248	918		
439	110122		
439	17		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	* -		
	ce search printout	1/23/2006	ML

SEAR((INCLUDING SE	CH NOTES EARCH STRATEGY)		
	DATE			
EAST	11/11/2004	ML		
EAST updated	3/31/2005	ML		
Updated	8/23/2005	ML		
Updated	1/23/2006	ML		